Sunday 25th

9:00-17:00 (at the hotel "Il Chiostro")	**Tutorial 1**	**Tutorial 2**
	DFx: The convergence of test, manufacturing, and yield *Robert Altken*, ARM	**IEEE 1500 - Building a Compliant Wrapper** *T. McLaurin*, ARM *T. Waayers*, NXP
20:00	**Welcome reception at hotel Majestic with lakeside Italian flavors buffet**	

Monday 26th

8:30-10:30	**ETS'08 Plenary Opening**		
10:30-11:00	*Coffee Break*		
11:00-12:30	**Session 2A** Testing and Monitoring for High Quality Requirements	**Session 2B** SoC Infrastructure	**Session 2C** Vendor ATE Architectures
12:30-14:00	*Lunch*		
14:00-15:30	**Session 3A** Advances in RF Testing	**Session 3B** Safe Test Generation and Design Validation	**Session 3C** Vendor Parallel Testing
15:30-16:30	**Session 4 – Posters and Coffee Break**		
16:30-18:00	**Session 5A** News from Memory Test	**Session 5B** Diagnosis: New Concepts and Industrial Application	**Session 4C** Vendor The power of DfT
18:00-19:30	**Session 6A - Panel 1** Commercial tools for RTL Design-for-Test exist but how good are they?	**Session 6B - Panel 2** No Beginners Beyond this Point	
	Evening in Pizzeria		

Tuesday 27th

8:30-10:00	**Session 7A** Delay Faults: Simulation, Test Generation and DFT	**Session 7B** SoC Testing	**Session 7C** Vendor Potpourri
10:00-11:00	**Session 8 - Posters and Coffee Break**		
11:00-12:30	**Session 9A** On-Chip Resources for Mixed-Signal Devices	**Session 9B** Special Session 1 NASA Flatsats: Spacecraft Testbeds for Mission Success	**Session 9C** Vendor Test Engineering
12:30-14:00	*Lunch*		
14:00-15:00	**Session 10A** Embedded Tutorial 1 Post-Silicon Validation and Debug	**Session 10B** Embedded Tutorial 2 Update: the P1687 (IJTAG) Hardware Proposal for Efficient Embedded Instrument Access, Bandwidth, and Connectivity – the ABC's of Embedded Content	**Session 10C** Embedded Tutorial 3 DFT/BIST Circuit Techniques Using Sigma-Delta Encoding Methods
16:00	**Social Program**		

Wednesday 28th	8:30-10:00	**Session 11A** Solutions for Yield Enhancement	**Session 11B** Online Checking	**Session 11C** Vendor Design-for-Test
	10:00-11:00	**Session 12 -** Posters *and Coffee Break*		
	11:00-12:30	**Session 13A** Embedded Tutorial 4		**Session 13B** Special Session 2
		Reliability, Availability and Serviceability of Networks-on-Chip		Collaborative Test Research in Europe
	12:30-14:00	*Lunch*		
	14:00-15:30	**Session 14** Soft Error Mitigation		
	16:00	**ETS'08 Closing Session**		

Thursday 29th		Fringe Workshops Day	
	8:30-17:00	**Workshop on Reliability & DfX Engineering for System-in-Package Technologies - SiPeX**	**Workshop on Low Power Design Impact on Test and Reliability - LPonTR**

13th IEEE European Test Symposium

Verbania, ITALY, May 25-29, 2008